

November 2013

# FDMS86350

# N-Channel PowerTrench<sup>®</sup> MOSFET 80 V, 130 A, 2.4 m $\Omega$

## **Features**

- Max  $r_{DS(on)}$  = 2.4 m $\Omega$  at  $V_{GS}$  = 10 V,  $I_D$  = 25 A
- Max  $r_{DS(on)} = 3.2 \text{ m}\Omega$  at  $V_{GS} = 8 \text{ V}$ ,  $I_D = 22 \text{ A}$
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- MSL1 robust package design
- 100% UIL tested
- RoHS Compliant

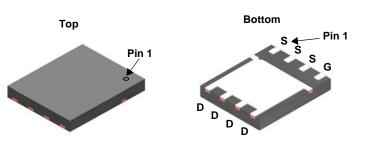


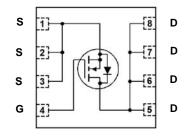
## **General Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

## **Applications**

- Primary MOSFET
- Synchronous Rectifier
- Load Switch
- Motor Control Switch





Power 56

# **MOSFET Maximum Ratings** $T_A = 25$ °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			80	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous	T <sub>C</sub> = 25 °C		130	
$I_D$	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	25	Α
	-Pulsed		(Note 4)	300	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	864	mJ
В	Power Dissipation $T_C = 25 ^{\circ}\text{C}$			156	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.7	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.8	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	45	C/VV

#### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86350	FDMS86350	Power 56	13 "	12 mm	3000 units

## **Electrical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		45		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 64 V, V <sub>GS</sub> = 0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

## **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.5	3.8	4.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		-12		mV/°C
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 25 A		2.0	2.4	
r <sub>DS(on)</sub>	20(0.1)	$V_{GS} = 8 \text{ V}, I_D = 22 \text{ A}$		2.5	3.2	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 25 \text{ A}, T_J = 125 \text{ °C}$		3.1	3.8	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 25 A		70		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 40.V V 0.V		8030	10680	pF
Coss	Output Capacitance	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1  MHz		1370	1825	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12		31	50	pF
R <sub>a</sub>	Gate Resistance		0.1	1.1	3	Ω

## **Switching Characteristics**

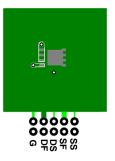
t <sub>d(on)</sub>	Turn-On Delay Time		50	80	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 40 V, I <sub>D</sub> = 25 A,	34	55	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	40	65	ns
t <sub>f</sub>	Fall Time		11	20	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	110	155	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to 8 V}$ $V_{DD} = 40 \text{ V},$	90	127	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = 25 A	46		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		23		nC

#### **Drain-Source Diode Characteristics**

V <sub>SD</sub> Source to Drain	Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)	0.71	1.2	V
	Source to Drain blode Forward voltage	$V_{GS} = 0 \text{ V}, I_S = 25 \text{ A}$ (Note 2)	0.79	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	- I <sub>E</sub> = 25 A, di/dt = 100 A/μs	63	101	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = 23 A, αι/αι = 100 A/μS		100	nC

#### Notes:

<sup>1.</sup> R<sub>BJA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>BJC</sub> is guaranteed by design while R<sub>BCA</sub> is determined by the user's board design.



a. 45 °C/W when mounted on a
 1 in<sup>2</sup> pad of 2 oz copper.



 b. 115 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu\text{s},$  Duty cycle < 2.0%.

<sup>3.</sup>  $E_{AS}$  of 864 mJ is based on starting  $T_{J} = 25$  °C, L = 3 mH,  $I_{AS} = 24$  A,  $V_{DD} = 80$  V,  $V_{GS} = 10$  V, 100% test at L = 0.1 mH,  $I_{AS} = 74$  A.

<sup>4.</sup> Pulse Id limited by junction temperature, td <= 100  $\mu$ s, please refer to SOA curve for more details.

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

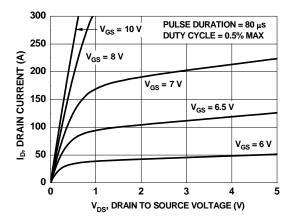


Figure 1. On-Region Characteristics

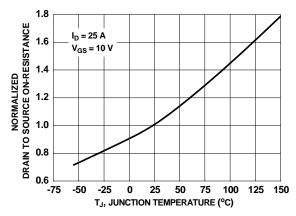


Figure 3. Normalized On-Resistance vs Junction Temperature

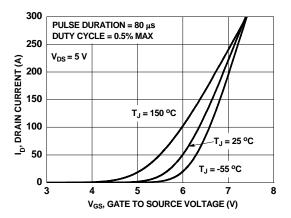


Figure 5. Transfer Characteristics

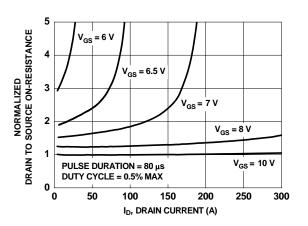


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

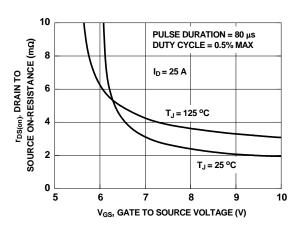


Figure 4. On-Resistance vs Gate to Source Voltage

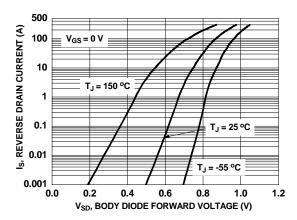


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

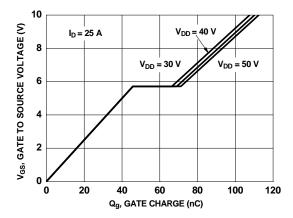


Figure 7. Gate Charge Characteristics

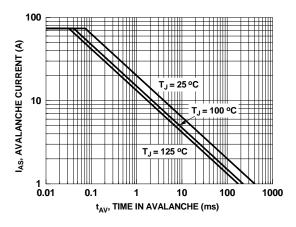


Figure 9. Unclamped Inductive Switching Capability

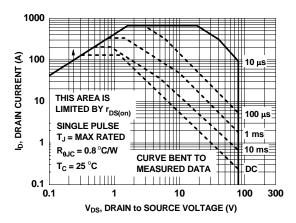


Figure 11. Forward Bias Safe Operating Area

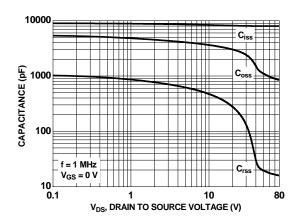


Figure 8. Capacitance vs Drain to Source Voltage

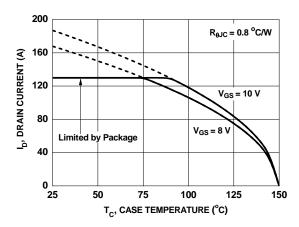


Figure 10. Maximum Continuous Drain Current vs Case Temperature

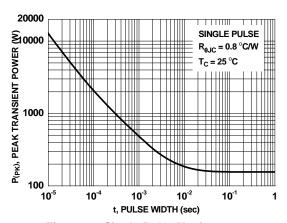


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

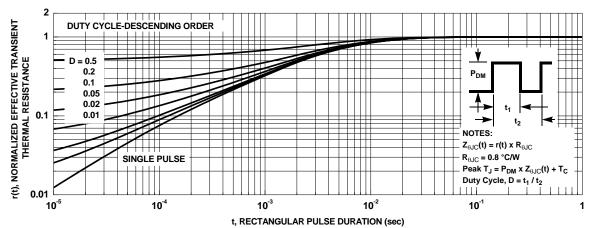
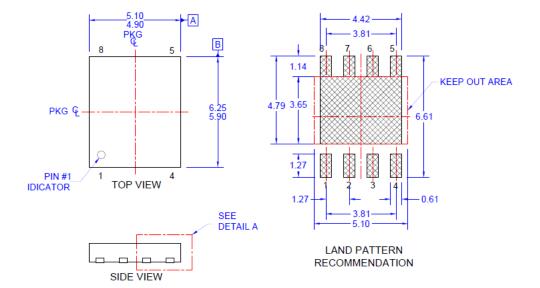
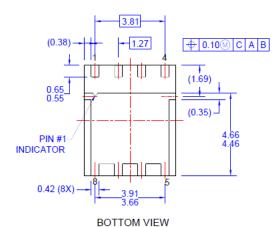
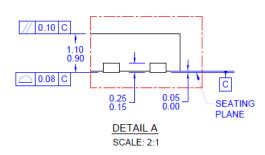


Figure 13. Junction-to-Case Transient Thermal Response Curve

## **Dimensional Outline and Pad Layout**







#### NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE:
  JEDEC MO-240, ISSUE A, VAR. AA,
  B) ALL DIMENSIONS ARE IN MILLIMETERS.
  C) DIMENSIONS DO NOT INCLUDE BURRS
- OR MOLD FLASH. MOLD FLASH OR BURRS DOES NOT EXCEED 0.10MM
- D) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.
- E) IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.
- F) DRAWING FILE NAME: PQFN08JREV1.





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